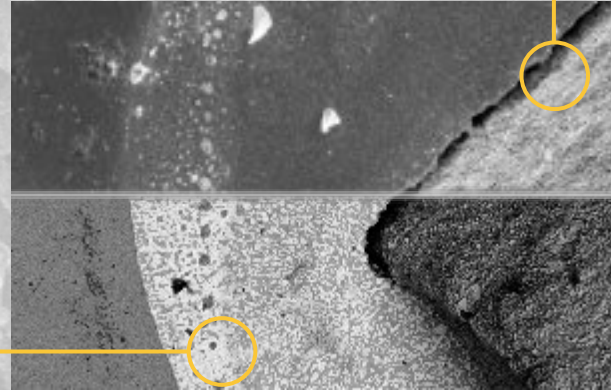


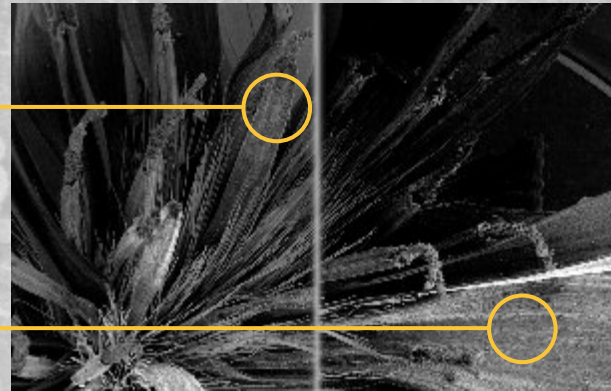
Coxem Tabletop SEM

The tabletop SEM combines the **small footprint** and the ease-of-use of a Light Microscope with the high resolution and the analytical capabilities of a conventional Electron Microscope. Aided by the integrated navigation camera and its automatic functions, you can locate your sample, define your region of interest, and record the image in seconds.

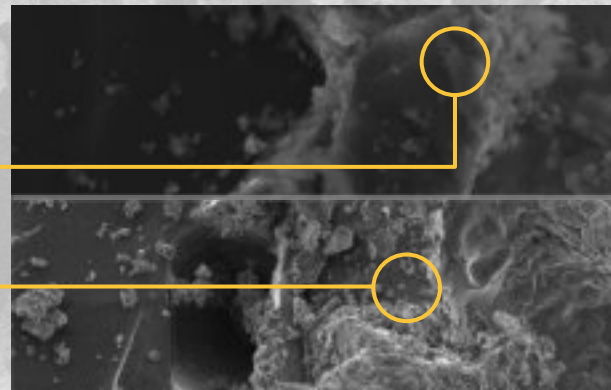
The device includes two detectors as standard: the **Secondary Electron (SE)** detector for topographical information, and the **Backscatter Electron (BSE)** detector for different material compositions such as particles or inclusions.



The system can be operated in both high and low vacuum modes. **High vacuum** is ideal for high resolution images of conductive or coated samples. **Low vacuum** mode is used for insulating specimens because the lower vacuum will neutralize the charge on the surface.

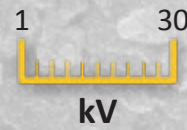


The COXEM has a wide range of acceleration voltages. This is a great advantage when imaging different types of samples. **Low voltages** (below 5kV) enable high resolution imaging of surface sensitive samples, whereas **higher voltages** (up to 30kV) allow clear detection of heavier elements during EDX measurements, or the detection of sub-surface structures.

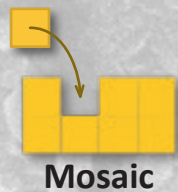


Specifications

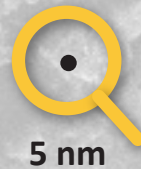
Model	EM-30 AXN
Footprint	40 x 63 cm
Magnification	20 – 100'000 x
Resolution	Down to 5 nm
Acceleration Voltage	3 – 30 kV
Electron Source	Tungsten Filament
Detector	Secondary electron detector 4 Channel Backscatter Detector (Compo, Topo)
Sample Stage	3 motorized axes x, y, R,
Sample Size	70 mm (W) x 45 mm (H)
X/Y Traverse	35 mm x 35 mm
Operation	Mouse, Keyboard, SpaceMouse



High Vacuum
Low Vacuum



Mosaic



5 nm



EDX

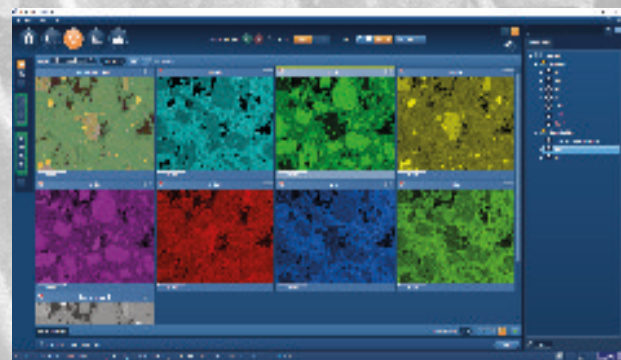
The COXEM SEM can be extended with a microanalysis system that enables qualitative and quantitative analysis of your sample. This system consists of an X-Ray detector, hardware and the AZTec Software, including different modes such as mapping and line scans.

- Reliable automatic element identification
- Accurate quantification of homogenous material
- Excellent detection of light elements from Be
- Fast analysis due to the 30mm² active detector area
- Maintenance free



Point & ID

Quick routine analysis with a point or surface analysis – detection of elements and their composition



Map

Marks the location of elements across a region of interest by different colors. A high intensity level indicates a high concentration of an element

GLOOR INSTRUMENTS

Tabletop SEM

COXEM EM-30AXN

Quick Access to the Nano Scale



Over 40 years market presence – your most reliable partner in microscopy



Collaboration with established and high-quality suppliers



Instrument evaluation with the support of our experts



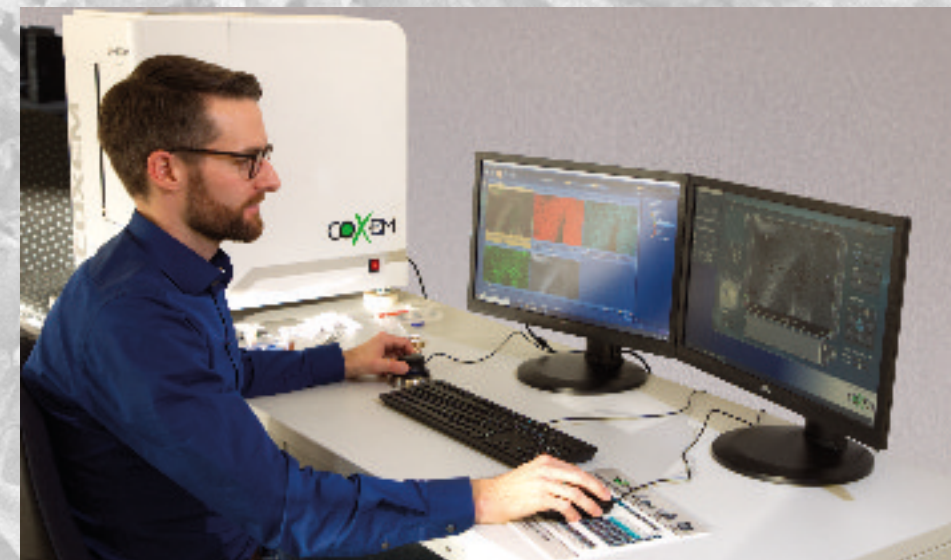
Installation and training



Local and on-site support



User Meetings to share experience



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